

<b>Notice of References Cited</b>	Application/Control No. 10/573,915		Applicant(s)/Patent Under Reexamination SHIRAKASHI ET AL.	
	Examiner YEWEBDAR T. TADESSE		Art Unit 1792	Page 1 of 1

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*	A	US-2002/0081118 A	06-2002	Sakurai et al.	396/564
*	B	US-2005/0084606	04-2005	Park et al.	427/162
*	C	US-6,709,699	03-2004	Ema et al.	427/240
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#### NON-PATENT DOCUMENTS

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